

FORM PTO-1449 (Modified)

ATTY. DOCKET NO.  
TS1099

APPLICATION NUMBER

10/509418

LIST OF INFORMATION PROVIDED  
BY APPLICANT

(Use several sheets if necessary)

APPLICANT  
PUIK, Eric, JohannesFILING DATE  
September 24, 2004GROUP ART UNIT  
2855

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Patentee	Class	Subclass	Filing Date if Appropriate
CW	AA	4660414	4/28/87	Gregory J. Hatton, et al	73	61.1	9/12/85
	AB	5378353	1/3/95	Berthold Koch	210	86	1/8/93
	AC	4563274	1/7/86	Stephen Rothon, et al	210	101	8/20/84
	AD	4698152	10/6/87	Noel Carroll	210	96.01	8/3/84
	AE	5064448	11/12/91	Michael S. Choi	55	38	1/9/91
	AF	4708793	11/24/87	Richard L. Cathriner, et al	210	188	6/13/86
	AG	6468335	10/22/02	Hugo G. Poldermann	96	183	4/12/00
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Subclass	Translation	
							Yes	No
CW	AL	1044711	10/18/00	EP	B01D	17/025		
CW	AM	2077364 Database XP-002116078	4/20/97	RU and (English abstract)	B01D9	19/00		X
	AN							
	AO							

## OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

✓	AR	International Search Report dated 26 June 2003
	AS	
	AT	

EXAMINER

DATE CONSIDERED

1/24/06

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

1. The attached cited information should not be construed as an admission that any of the above items are prior

FORM PTO-1449 (Modified)

ATTY. DOCKET NO.  
TS1099APPLICATION NUMBER  
10/509,418LIST OF INFORMATION PROVIDED  
BY APPLICANT

(Use several sheets if necessary)

APPLICANT  
PUIK, Eric, JohannesFILING DATE  
September 24, 2004GROUP ART UNIT  
2855

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Patentee	Class	Subclass	Filing Date if Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							

## OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

	AR	Kirk-Othmer, Encyclopedia of Chemical Technology, NY, 4 <sup>th</sup> Edition, Vol. 15, 1995, pp. 409-433
	AS	
	AT	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

1. The attached cited information should not be construed as an admission that any of the above items are prior